

# ZL40241

# Ten LVCMOS Output Low Additive Jitter Fanout Buffer

#### Features

- 3-to-1 Input Multiplexer: Two Inputs Accept Any Differential (LVPECL, HCSL, LVDS, SSTL, CML, LVCMOS) or a Single Ended Signal and the Third Input Accepts a Crystal or a Single Ended Signal
- Ten 1.5V/1.8V/2.5V/3.3V LVCMOS Outputs
- Supports Frequencies from 0 MHz to 200 MHz
- Supports Crystals from 8 MHz to 60 MHz
- Ultra-Low Additive Jitter: 17 fs (12 kHz to 20 MHz)
- Ultra-Low Noise Floor of -170 dBc/Hz
- Supports 2.5V or 3.3V Power Supplies
- Output to Output Skew of 30 ps (Typical)
- Input to Output Delay of 2 ns (Typical)

#### Applications

- General Purpose Clock Distribution
- Low Jitter Clock Trees
- Logic Translation
- Clock and Data Signal Restoration
- Wired and Wireless Communications
- High Performance Microprocessor Clock Distribution
- Medical Imaging
- Test Equipment

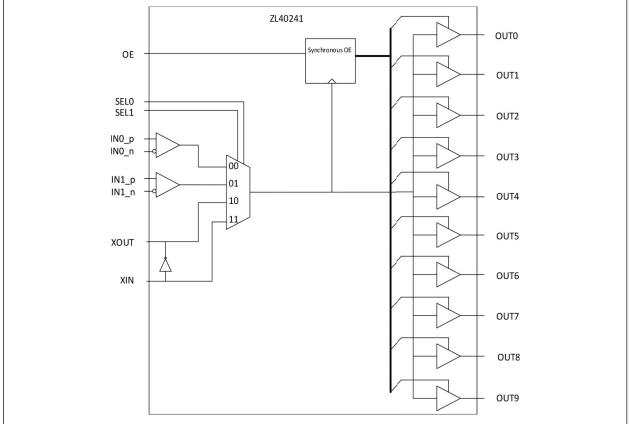


FIGURE 0-1: Functional Block Diagram.

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#### 1.0 PIN DESCRIPTION AND CONFIGURATION

The device is packaged in a 5 mm × 5 mm 32-lead VQFN.

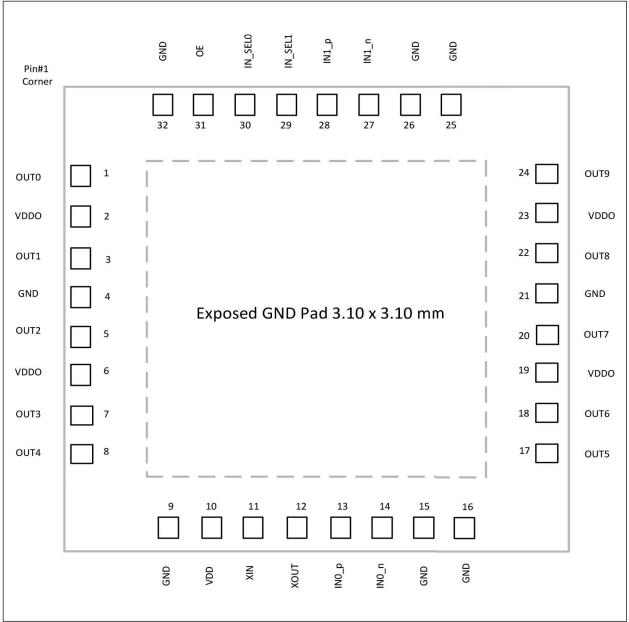


FIGURE 1-1:

32-Lead 3.10 mm × 3.10 mm VQFN with E-Pad.

All device inputs and outputs are LVPECL unless described otherwise. The I/O column uses the following symbols: I – input,  $I_{PU}$  – input with 300 k $\Omega$  internal pull-up resistor,  $I_{PD}$  – input with 300 k $\Omega$  internal pull-down resistor,  $I_{APU}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input with 30 k $\Omega$  internal pull-up resistor,  $I_{APD}$  – input biased at VDD/2 with 60 k $\Omega$  internal pull-up and 60 k $\Omega$  pull-down resistors, O – output, I/O – Input/Output pin, P – power supply pin.

Pin Number	Pin Name	Туре	Description							
Input Refer	ences									
13	IN0_p	I <sub>APD</sub>	Input Differential or Si	Input Differential or Single Ended References 0 and 1						
14	IN0_n	I <sub>APU/APD</sub>								
28	IN1_p	I <sub>APD</sub>	Input frequency range (	Input frequency range 0 Hz to 200 MHz.						
27	IN1_n	I <sub>APU/APD</sub>	Non inverting inputs (_p) are pulled down with internal 30 k $\Omega$ pull-down resistors. Inverting inputs (_n) are biased at VDD/2 with 60 k $\Omega$ pull-up and pull-down resistors to keep inverting input voltages at VDD/2 when inverting inputs are left floating (device fed with a single ended reference).							
Output Clo	cks									
1	OUT0									
3	OUT1									
5	OUT2									
7	OUT3									
8	OUT4	0	Ultra Low Additive Jit	Ultra Low Additive Jitter LVCMOS Outputs 0 to 9 Output frequency range 0 Hz to 200 MHz.	0 to 9					
17	OUT5	0	Output frequency range							
18	OUT6									
20	OUT7									
22	OUT8									
24	OUT9									
Control	•									
			Input Select Pins. Log passed to the output.	ic level on these pins s	elects which input will be					
			IN_SEL1	IN_SEL0	OUTN					
30	IN_SEL0		0	0	Input 0 (IN0)					
29	IN_SEL1	I <sub>PD</sub>	0	1	Input 1 (IN1)					
			1	0	Crystal Oscillator or Overdrive					
			1	1	Crystal Bypass					
31	OE	I <sub>PD</sub>	Output Enable. When high-Z.	high outputs are enabl	ed. When low outputs are					
Crystal Osc	illator		-							
11	XIN	I	Crystal Oscillator Inpu drive Mode. If crystal o it to ground.		Mode or Crystal Over- Il down this pin or connect					
12	XOUT	0	Crystal Oscillator Output.							
Power and	Ground		-							
10	VDD	Р	Positive Supply Voltage must be higher or equa		2.5V supply. VDD voltage					

TABLE 1-1: PIN DESCRIPTIONS

Pin Number	Pin Name	Туре	Description
2			
6	VDDO	Р	Positive Supply Voltage for LVCMOS Outputs. Connect 3.3V, 2.5V,
19		F	1.8V or 1.5V power supply.
23			
4			
9			
15			
16			
21	GND	Р	Ground. Connect to ground.
25			
26			
32			
E-Pad			

#### TABLE 1-1: PIN DESCRIPTIONS (CONTINUED)

#### 2.0 FUNCTIONAL DESCRIPTION

The ZL40241 is a programmable or hardware pin controlled low additive jitter, low power 3 × 10 LVCMOS fanout buffer.

Two inputs can accept signal in differential (LVPECL, SSTL, LVDS, HSTL, CML) or single ended (LVPECL or LVCMOS) format and the third input can accept a single ended signal or it can be used to build a crystal oscillator by connecting an external crystal resonator between its XIN and XOUT pins.

The ZL40241 has ten LVCMOS outputs which can be powered from 3.3V, 2.5V, 1.8V, or 1.5V supply. Output can be synchronously enabled/disabled via OE pin.

The device operates from 2.5V+/-5% or 3.3V+/-5% supply. Its operation is guaranteed over the industrial temperature range -40°C to +85°C.

#### 2.1 Clock Inputs

The following block diagrams show how to terminate different signals fed to the ZL40241 inputs. Figure 2-1 shows how to terminate a single ended output such as LVCMOS. Ideally, resistors R1 and R2 should be  $100\Omega$  each so that the transmission line is terminated with matched impedance (50 $\Omega$ ). However, if the driving strength of the output driver is not sufficient resistor values should be increased.

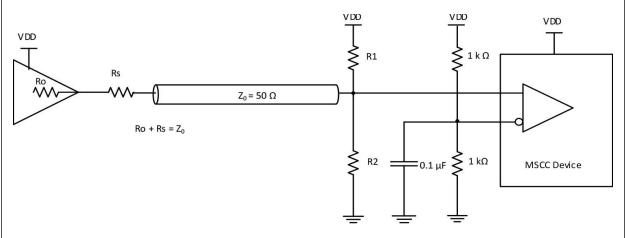


FIGURE 2-1: Input Driven by a Single-Ended Output.

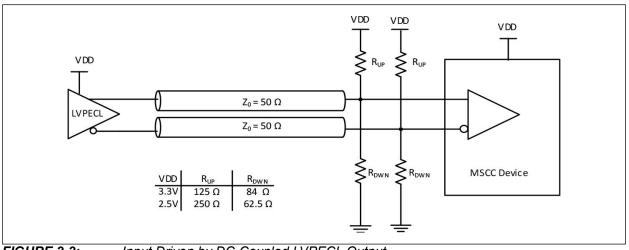
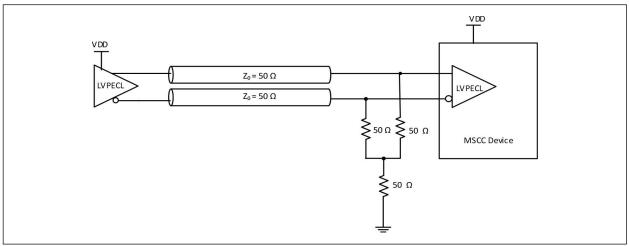


FIGURE 2-2:

Input Driven by DC-Coupled LVPECL Output.





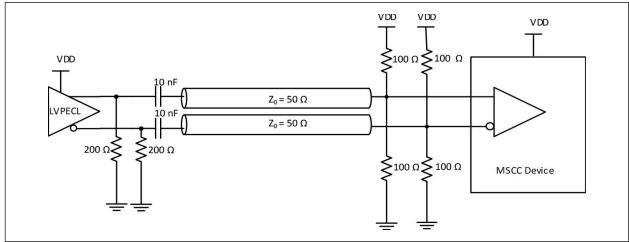


FIGURE 2-4: Input Driven by AC-Coupled LVPECL Output.

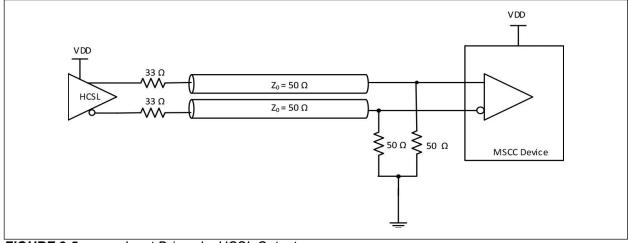
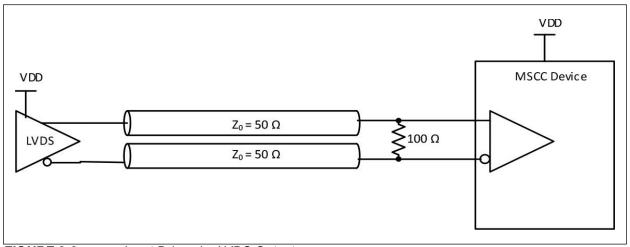
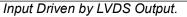
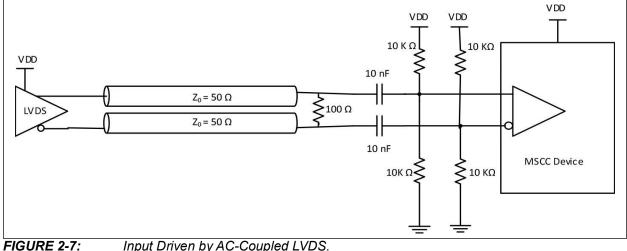


FIGURE 2-5: Input Driven by HCSL Output.

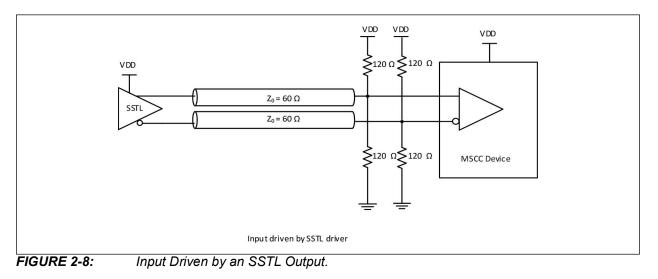








Input Driven by AC-Coupled LVDS.



#### 2.2 Clock Outputs

LVCMOS outputs require only series termination resistor whose value is depending on LVCMOS output voltage as shown in Figure 2-9.

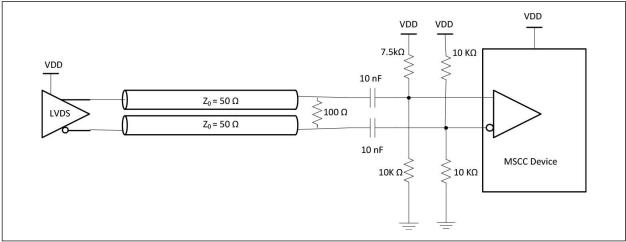


FIGURE 2-9: Termination for LVCMOS Outputs.

#### 2.3 Crystal Oscillator Input

The crystal oscillator circuit can work with crystal resonators from 8 MHz to 160 MHz. Load capacitors C1 and C2 shall be selected as per crystal vendor recommendation. Shunt resistor is implemented inside the device. If the crystal is not used, connect XIN pin to ground.

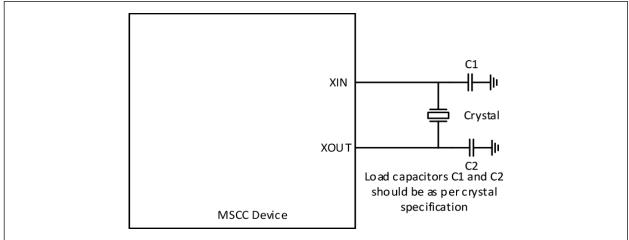


FIGURE 2-10: Crystal Oscillator Circuit in Hardware Controlled Mode.

The phase noise plot for 25 MHz crystal is shown in Figure 2-11. The phase noise floor of the device is below 170 dBc/Hz as can be seen on the figure.

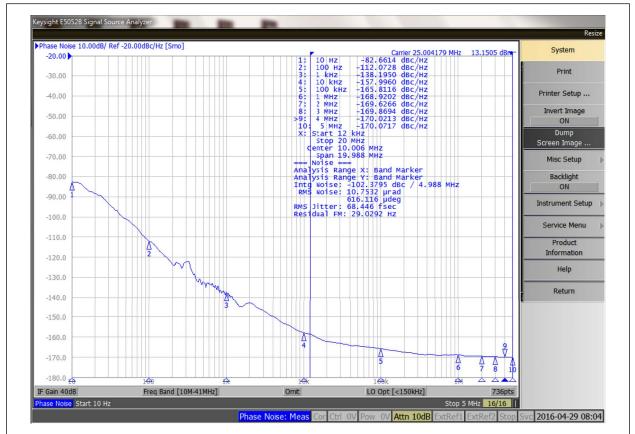


FIGURE 2-11: Phase Noise Plot with 25 MHz Crystal.

#### 2.4 Termination of Unused Inputs and Outputs

Unused inputs can be left unconnected or alternatively IN\_0/1 can be pulled-down by 1 K $\Omega$  resistor. Unused outputs should be left unconnected.

#### 2.5 **Power Consumption**

The total device power consumption can be calculated as:

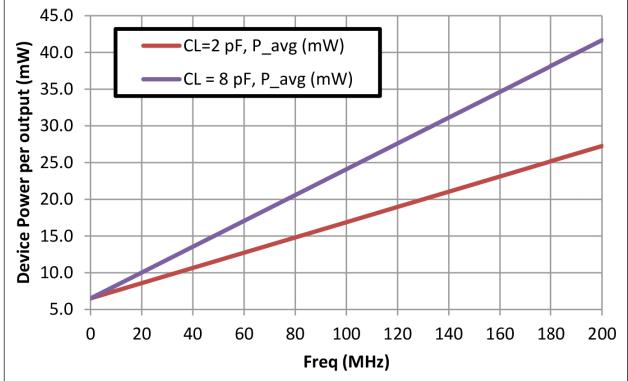
#### EQUATION 2-1:

$$P_T = P_S + P_{XTAL} + P_C + P_L$$

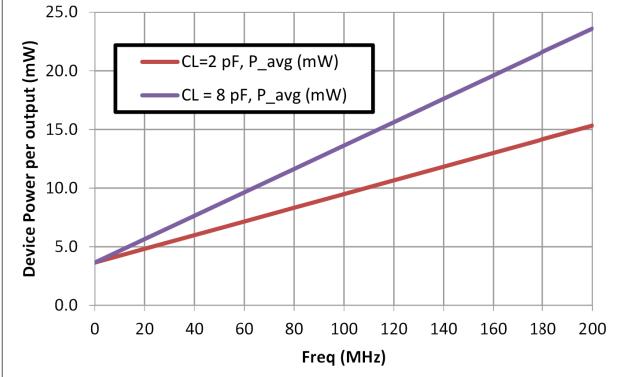
Where:	
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$P_{S} = V_{DD} \times I_{S}$	This is static power consumed by input buffers. If XTAL is running, this power should be set to zero. The static current $(I_S)$ is specified in Table 3-2.
$P_{XTAL} = V_{DD} \times I_{DD_{XTAL}}$	This is the power consumption of the XTAL circuit. The current of the XTAL circuit is provided in Table 3-2. If XTAL is not used, the power consumption is equal to zero.
$P_{C} = V_{DDO} \times I_{DDC}$	Common output power shared among all ten outputs. The current $I_{\text{DDC}}$ is specified in Table 3-2.
$P_{D} = V_{DDO} \times (I_{DD} \times n \times f / 100 \text{ MHz} + V_{DD} \times C_{LOAD} \times f \times n)$	Dynamic power where dynamic current $(I_{DD})$ is specified in Table 3-2. $C_{LOAD}$ is capacitive load driven by an output, f is frequency of hte output clock and n is number of active outputs.

The power consumption for different clock frequencies and power supply voltages can be quickly estimated from Figure 2-12, Figure 2-13, and Figure 2-14.



**FIGURE 2-12:** Device Power Consumption per Output for  $V_{DD} = V_{DDO} = 3.465V$ .



**FIGURE 2-13:** Device Power Consumption per Output for  $V_{DD} = V_{DDO} = 2.625V$ .

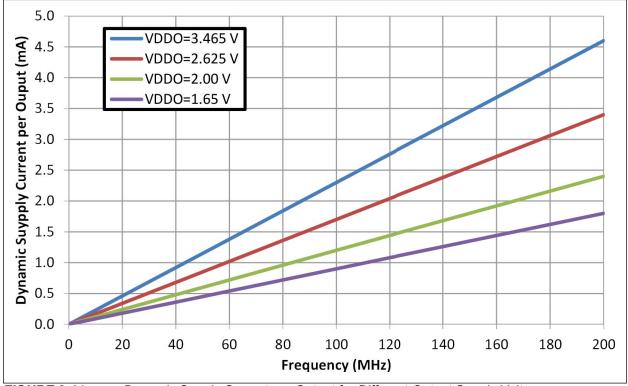


FIGURE 2-14: Dynamic Supply Current per Output for Different Output Supply Voltages.

#### 2.6 Power Supply Filtering

Each power pin (VDD and VDDO) should be decoupled with 0.1 µF capacitor with minimum equivalent series resistance (ESR) and minimum series inductance (ESL). For example, 0402 X5R Ceramic Capacitors with 6.3V minimum rating could be used. These capacitors should be placed as close as possible to the power pins. To reduce the power noise from adjacent digital components on the board, each power supply could be further insulated with low resistance ferrite bead with two capacitors. The ferrite bead will also insulate adjacent component from the noise generated from the device. Figure 2-15 shows the recommended decoupling for each power pin.

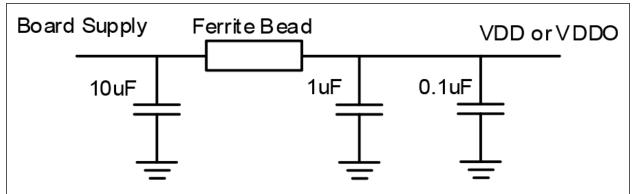


FIGURE 2-15: Power Supply Filtering.

#### 2.7 Device Control

ZL30241 is controlled via Output Enable (OE) and Input Select (SEL0/1) input pins.

NOTES:

# 3.0 ELECTRICAL CHARACTERISTICS

#### TABLE 3-1: ABSOLUTE MAXIMUM RATINGS (Note 1, Note 2, Note 3)

Parameter	Symbol	Min.	Max.	Units
Supply voltage, 3.3V	V <sub>DD</sub> /V <sub>DDO</sub>	-0.5	+4.6	V
Supply voltage, 2.5V	V <sub>DD</sub> /V <sub>DDO</sub>	-0.5	+4.6	V
Supply voltage, 1.8V	V <sub>DDO</sub>	-0.5	+2.5	V
Supply voltage, 1.5V	V <sub>DDO</sub>	-0.5	+2.0	V
Storage temperature range	T <sub>ST</sub>	-55	+125.0	°C

Note 1: Exceeding these values may cause permanent damage.

2: Functional operation under these conditions is not implied.

**3:** Voltages are with respect to ground (GND) unless otherwise stated.

#### TABLE 3-2: RECOMMENDED OPERATING CONDITIONS (Note 1, Note 2)

Parameter	Symbol	Min.	Тур.	Max.	Units
Supply voltage, 3.3V	V <sub>DD</sub> /V <sub>DDO</sub>	3.135	3.300	3.465	V
Supply voltage, 2.5V	V <sub>DD</sub> /V <sub>DDO</sub>	2.375	2.500	2.625	V
Supply voltage, 1.8V	V <sub>DDO</sub>	1.600	1.800	2.000	V
Supply voltage, 1.5V	V <sub>DDO</sub>	1.350	1.500	1.650	V
Operating temperature	T <sub>A</sub>	-40.000	+25.000	+85.000	°C
Input voltage	V <sub>DD-IN</sub>	-0.300		V <sub>DD</sub> + 0.300	V

Note 1: Voltages are with respect to ground (GND) unless otherwise stated.

**2:** The device supports two power supply modes (3.3V and 2.5V).

#### TABLE 3-3:CURRENT CONSUMPTION

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes
Static device current	I <sub>S_3.3V</sub>	—	15	18	mA	V <sub>DD</sub> = 3.465V
	I <sub>S_2.5V</sub>	—	12	15	mA	V <sub>DD</sub> = 2.625V
Device current with 25 MHz XTAL input	IDD_XTAL_3.3V	—	24	27	mA	V <sub>DD</sub> = 3.465V
	IDD_XTAL_2.5V	_	18	20	mA	V <sub>DD</sub> = 2.625V
Dynamic current per output (f = 100MHz),	I <sub>DD_3.3V</sub>	—	4.2	4.7	mA	V <sub>DD</sub> = 3.465V
Note 1, Note 2	I <sub>DD_2.5V</sub>	—	3.0	3.5	mA	V <sub>DD</sub> = 2.625V
Needs to be scaled for different frequen- cies by f/100 MHz, Driving Strength = 1	I <sub>DD_1.8V</sub>	—	2.1	2.4	mA	V <sub>DD</sub> = 2.000V
(registers 0x09, 0x0A)	I <sub>DD_1.5V</sub>	—	1.6	1.8	mA	V <sub>DD</sub> = 1.650V
Dynamic current per output (f = 100MHz),	I <sub>DD_3.3V</sub>	—	2.3	3.0	mA	V <sub>DD</sub> = 3.465V
Note 1, Note 2 Needs to be scaled for different frequen- cies by f/100 MHz, Driving Strength = 0	I <sub>DD_2.5V</sub>	—	1.7	1.8	mA	V <sub>DD</sub> = 2.625V
	 I <sub>DD_1.8V</sub>		1.2	1.3	mA	V <sub>DD</sub> = 2.000V
(registers 0x09, 0x0A)	I <sub>DD_1.5V</sub>	_	0.9	1.0	mA	V <sub>DD</sub> = 1.650V

Note 1: Needs to be scaled for different frequencies by f/100 MHz.

2: To calculate total power consumption use following formula: P = (I<sub>S</sub> + I<sub>DD\_XTAL</sub>) × V<sub>DD</sub> + (I<sub>DDC</sub> + I<sub>DD</sub> × n × f/100 MHz + V<sub>DDO</sub> × C<sub>LOAD</sub> × f × n) × V<sub>DDO</sub>, where I<sub>DD\_XTAL</sub>: should be set to zero if XTAL is not used or Is should be set to zero if XTAL is used. Also, n = number of active outputs; f = frequency of the clock; C<sub>LOAD</sub> = capacitive load driven by an output.

**3:** This current is consumed by device whenever one or more outputs are enabled. It is independent of the number of active outputs.

#### TABLE 3-3: CURRENT CONSUMPTION (CONTINUED)

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes
Common output current, Note 3	I <sub>DD_3.3V</sub>	—	3.8	8.0	mA	V <sub>DD</sub> = 3.465V
	I <sub>DD_2.5V</sub>	—	1.9	3.3	mA	V <sub>DD</sub> = 2.625V
	I <sub>DD_1.8V</sub>	_	1.2	1.7	mA	V <sub>DD</sub> = 2.000V
	I <sub>DD_1.5V</sub>	_	1.0	1.4	mA	V <sub>DD</sub> = 1.650V

Note 1: Needs to be scaled for different frequencies by f/100 MHz.

2: To calculate total power consumption use following formula: P = (I<sub>S</sub> + I<sub>DD\_XTAL</sub>) × V<sub>DD</sub> + (I<sub>DDC</sub> + I<sub>DD</sub> × n × f/100 MHz + V<sub>DDO</sub> × C<sub>LOAD</sub> × f × n) × V<sub>DDO</sub>, where I<sub>DD\_XTAL</sub>: should be set to zero if XTAL is not used or Is should be set to zero if XTAL is used. Also, n = number of active outputs; f = frequency of the clock; C<sub>LOAD</sub> = capacitive load driven by an output.

**3:** This current is consumed by device whenever one or more outputs are enabled. It is independent of the number of active outputs.

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes
CMOS high-level input voltage for SPI_CLK, SPI_CS and SPI_SDI	V <sub>CIH</sub>	1.20	_	_	V	_
CMOS low-level input voltage for SPI_CLK, SPI_CS and SPI_SDI	V <sub>CIL</sub>	_	_	0.45	V	
CMOS input leakage current for SPI_CLK, SPI_CS and SPI_SDI, Note 3	Ι <sub>ΙL</sub>	-40	_	10	μA	VI = VDD or 0 V
Differential input common mode voltage for IN0_p/n and IN1_p/n	V <sub>CM</sub>	0.5	_	V <sub>DD</sub> – 0.85	V	_
Differential input voltage difference for IN0_p/n and IN1_p/n	V <sub>ID</sub>	0.15	_	1.3	V	
Differential input leakage current for IN0_p/n and IN1_p/n (includes current in pull-up and pull-down resistors), Note 4	IIL	-200	_	100	μΑ	VI = VDD or 0 V
Single ended input high voltage for	V <sub>SIH</sub>	2	_	V <sub>DD</sub> + 0.3	V	VDD = 3.3V+/-5%
IN_0_p and IN_1_p	V SIH	1.6	—	V <sub>DD</sub> + 0.3	V	VDD = 2.5V+/-5%
Single ended input low voltage for	M	-0.3	—	1.3	V	VDD = 3.3V+/-5%
IN_0_p and IN_1_p	V <sub>SIL</sub>	-0.3	—	0.9	V	VDD = 2.5V+/-5%
Input frequency	f <sub>IN</sub>	0	—	200	MHz	—
Input duty cycle (200 MHz Input Clock)	DC	35	—	65	%	Note 5
Input slew rate	slew	_	2		V/ns	—
Input pull-up/pull-down resistance	R <sub>PU</sub> /R <sub>PD</sub>		60 kΩ		kΩ	_
Input pull-down resistance (INx_p)	R <sub>PD</sub>	—	30 kΩ		kΩ	_

#### TABLE 3-4: INPUT CHARACTERISTICS (Note 1, Note 2)

**Note 1:** Values are over recommended operating conditions.

2: Values are over all two power supply modes (V<sub>DD</sub> = 3.3V and V<sub>DD</sub> = 2.5V).

3: CMOS input leakage is due to 300 kΩ pull-up/pull-down resistors.

**4:** Differential input leakage is due to 60 kΩ pull-up/pull-down resistors INx\_n and due to 30 kΩ pull-down resistor for INx\_p.

**5:** Minimum and maximum duty cycles should be scaled for different input frequencies. For example, a 10 MHz input clock would have the minimum duty cycle of 2% and the maximum duty cycle of 98%.

TABLE 3-5:	<b>CRYSTAL OSCILLATOR CHARACTERISTICS (</b>	Note 1)	)

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes
Mode of oscillation	mode	Fι	undame	ntal	_	—
Frequency	f	8	_	160	MHz	—
On chip shunt resistor	R	—	0.5	_	MΩ	—
On chip capacitance	С	—	12		pF	—
Frequency in overdrive mode, Note 2	f <sub>OV</sub>	0.1		200	MHz	Functional but may not meet AC parameters. Minimum depends on AC coupling. Capacitor (0.1 uF assumed).
Frequency in bypass mode, Note 3	f <sub>BP</sub>	—		200	MHz	Functional but may not meet AC parameters.

Note 1: Values are over recommended operating conditions. Values are over all two power supply modes ( $V_{DD}$  = 3.3V and  $V_{DD}$  = 2.5V).

- 2: Maximum input level is 2.0V.
- **3:** Maximum output level is V<sub>DD</sub>.

TABLE 3-6:	LVCMOS OUTP	UT CHA	RACTERIST	ICS (I	Note 1)

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes
		0.8 × V <sub>DDO</sub>	—		V	V <sub>DDO</sub> = 3.3V±5%
Output high voltage	V	$0.8 \times V_{DDO}$	—	_	V	V <sub>DDO</sub> = 2.5V±5%
Output high voltage	V <sub>OH</sub>	$0.7 \times V_{DDO}$	_	_	V	V <sub>DDO</sub> = 1.8V±10%
		$0.7 \times V_{DDO}$	—	_	V	V <sub>DDO</sub> = 1.5V±10%
		_	_	$0.2 \times V_{DDO}$	V	V <sub>DDO</sub> = 3.3V±5%
Output low voltage		—	_	$0.2 \times V_{DDO}$	V	V <sub>DDO</sub> = 2.5V±5%
Output low voltage	V <sub>OL</sub>	—	—	$0.3 \times V_{DDO}$	V	V <sub>DDO</sub> = 1.8V±10%
		—	—	$0.3 \times V_{DDO}$	V	V <sub>DDO</sub> = 1.5V±10%
		—	17	—	Ω	V <sub>DDO</sub> = 3.3V
Output impedance	R <sub>O</sub>	—	21	_	Ω	V <sub>DDO</sub> = 2.5V
		_	30	_	Ω	V <sub>DDO</sub> = 1.8V
		—	42	_	Ω	V <sub>DDO</sub> = 1.5V
		3.19	5.14	6.33	V/ns	V <sub>DDO</sub> = 3.3V±5%
Output slew rate, rise or fall (20%	+ +	1.72	3.74	4.61	V/ns	V <sub>DDO</sub> = 2.5V±5%
to 80%)	t <sub>r</sub> , t <sub>f</sub>	1.64	2.52	3.32	V/ns	V <sub>DDO</sub> = 1.8V±10%
		1.20	1.96	2.54	V/ns	V <sub>DDO</sub> = 1.5V±10%
Output frequency	Fo	0	—	200	MHz	—
Output duty cycle		50.26	—	53.18	%	Input. duty-cycle 50%
Output enable or disable time		—	—	2	cycle	—
Output to output skew	t <sub>oosk</sub>	—	—	27	ps	—
Device-to-device output skew	t <sub>DOOSK</sub>		_	1.6	ns	—
Input to output delay	+	1.15	2.09	2.54	ns	VDD = 3.3V
Input to output delay	t <sub>IOD</sub>	1.57	2.27	2.77	ns	VDD = 2.5V
Input multiplexer isolation	ISO	75	_		dB	Tested with 125 MHz clocks

**Note 1:** Values are over recommended operating conditions. Values are over all two power supply modes ( $V_{DD}$  = 3.3V and  $V_{DD}$  = 2.5V). Load 50 $\Omega$  to  $V_{DDO}/2$ .

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes
		_	17		fs – RMS	$V_{DD}$ = 3.3V, $V_{DDO}$ = 3.3V f <sub>in</sub> = 125 MHz, single ended input
System level additive jitter,		_	31	_	fs – RMS	$V_{DD}$ = 2.5V, $V_{DDO}$ = 1.5V to 2.5V f <sub>in</sub> = 125 MHz, single ended input
Note 2		_	22	_	fs – RMS	V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V f <sub>in</sub> = 125 MHz, differential input
			37	_	fs – RMS	$V_{DD}$ = 2.5V, $V_{DDO}$ = 1.5V to 2.5V f <sub>in</sub> = 125 MHz, differential input
		_	45.18	93.11	fs – RMS	$V_{DD}$ = 3.3V, $V_{DDO}$ = 3.3V f <sub>in</sub> = 125 MHz, single ended input
Additive jitter, Note 3, Note 4		_	80.46	126.92	fs – RMS	$V_{DD}$ = 2.5V, $V_{DDO}$ = 1.5V to 2.5V f <sub>in</sub> = 125 MHz, single ended input
Additive Jittel, Note 5, Note 4		_	39.95	68.98	fs – RMS	V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V f <sub>in</sub> = 125 MHz, differential input
			67.18	117.26	fs – RMS	$V_{DD}$ = 2.5V, $V_{DDO}$ = 1.5V to 2.5V f <sub>in</sub> = 125 MHz, differential input
		_	-145.08	-138.67	dBc/Hz	@10 kHz, f <sub>in</sub> = 125 MHz, single ended input
		—	-152.46	-145.82	dBc/Hz	@100 kHz, f <sub>in</sub> = 125 MHz, single ended input
		_	-160.67	-155.66	dBc/Hz	@1 MHz, f <sub>in</sub> = 125 MHz, single ended input
		_	-162.66	-160.55	dBc/Hz	@10 MHz, f <sub>in</sub> = 125 MHz, single ended input
Phase noise floor (VDD = 3.3V,			-162.71	-160.19	dBc/Hz	@20 MHz, f <sub>in</sub> = 125 MHz, single ended input
VDDO = 3.3V)			-145.34	-137.83	dBc/Hz	@10 kHz, f <sub>in</sub> = 125 MHz, single ended input
		_	-152.60	-146.93	dBc/Hz	@100 kHz, f <sub>in</sub> = 125 MHz, single ended input
		_	-161.06	-156.99	dBc/Hz	@1 MHz, f <sub>in</sub> = 125 MHz, single ended input
		_	-163.22	-160.84	dBc/Hz	@10 MHz, f <sub>in</sub> = 125 MHz, single ended input
		_	-163.38	-161.42	dBc/Hz	@20 MHz, f <sub>in</sub> = 125 MHz, single ended input

#### LVCMOS OUTPUT ADDITIVE JITTER AND PHASE NOISE (Note 1) **TABLE 3-7:**

Note 1: Values are over recommended operating conditions. Values are over all two power supply modes (V<sub>DD</sub> = 3.3V and  $V_{DD} = 2.5V$ ).

2: System level additive jitter is calculated as  $J_{RMS\_SYS\_AJ} = J_{RMS\_OUT} - J_{RMS\_IN}$ . 3: Additive jitter is calculated as  $J_{RMS\_AJ} = \text{sqrt} (J_{RMS\_OUT}^2 - J_{RMS\_IN}^2)$  where jitter is integrated in 12 kHz to 20 MHz band.

4: Tester measures jitter at 156.25 MHz. Since this frequency won't appear in the data sheet, it should be removed from the PPGT. Data sheet jitter is guaranteed by lab char. The ATE jitter measurement will be used to screen outliers only, with limits based on ATE distribution.

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes		
		_	-139.93	-134.59	dBc/Hz	@10 kHz, f <sub>in</sub> = 125 MHz, single ended input		
		_	-147.22	-144.21	dBc/Hz	@100 kHz, f <sub>in</sub> = 125 MHz, single ended input		
			_	-157.11	-154.78	dBc/Hz	@1 MHz, f <sub>in</sub> = 125 MHz, single ended input	
				_	-160.58	-158.21	dBc/Hz	@10 MHz, f <sub>in</sub> = 125 MHz, single ended input
Phase noise floor (VDD = 2.5V,				_	-160.78	-158.19	dBc/Hz	@20 MHz, f <sub>in</sub> = 125 MHz, single ended input
VDDO = 2.5V)			—	-141.69	-134.26	dBc/Hz	@10 kHz, f <sub>in</sub> = 125 MHz, single ended input	
				_	-149.19	-144.73	dBc/Hz	@100 kHz, f <sub>in</sub> = 125 MHz, single ended input
						_	-158.66	-156.22
		_	-161.60	-159.32	dBc/Hz	@10 MHz, f <sub>in</sub> = 125 MHz, single ended input		
		_	-161.85	-159.36	dBc/Hz	@20 MHz, f <sub>in</sub> = 125 MHz, single ended input		

#### TABLE 3-7: LVCMOS OUTPUT ADDITIVE JITTER AND PHASE NOISE (Note 1) (CONTINUED)

Note 1: Values are over recommended operating conditions. Values are over all two power supply modes ( $V_{DD} = 3.3V$  and  $V_{DD} = 2.5V$ ).

2: System level additive jitter is calculated as  $J_{RMS_SYS_AJ} = J_{RMS_OUT} - J_{RMS_IN}$ .

**3:** Additive jitter is calculated as J<sub>RMS\_AJ</sub> = sqrt (J<sub>RMS\_OUT</sub><sup>2</sup> - J<sub>RMS\_IN</sub><sup>2</sup>) where jitter is integrated in 12 kHz to 20 MHz band.

4: Tester measures jitter at 156.25 MHz. Since this frequency won't appear in the data sheet, it should be removed from the PPGT. Data sheet jitter is guaranteed by lab char. The ATE jitter measurement will be used to screen outliers only, with limits based on ATE distribution.

Characteristics	Symbol	Min.	Тур.	Max.	Units	Notes
Jitter RMS in 12 kHz to			72.63		fs	V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
20 MHz band			87.59	—	fs	V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V
		—	-75.96	_	dBc/Hz	@10 Hz, V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
			-107.50	_	dBc/Hz	@100 Hz, V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
		—	-132.34	—	dBc/Hz	@1 kHz, V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
		—	-157.36		dBc/Hz	@10 kHz, V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
			-165.82	_	dBc/Hz	@100 kHz, V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
		—	-168.85	—	dBc/Hz	@1 MHz, V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
Phase noise floor		—	-168.88		dBc/Hz	@5 MHz, V <sub>DD</sub> = 3.3V, V <sub>DDO</sub> = 3.3V
Filase noise nooi		—	-70.52	—	dBc/Hz	@10 Hz, V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V
		—	-102.60	—	dBc/Hz	@100 Hz, V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V
		—	-129.14		dBc/Hz	@1 kHz, V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V
		—	-153.93	—	dBc/Hz	@10 kHz, V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V
			-164.00	—	dBc/Hz	@100 kHz, V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V
		_	-167.34		dBc/Hz	@1 MHz, V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V
		_	-167.41	_	dBc/Hz	@5 MHz, V <sub>DD</sub> = 2.5V; V <sub>DDO</sub> = 2.5V

#### TABLE 3-8: LVCMOS OUTPUT JITTER PHASE NOISE WITH 25 MHZ XTAL (NOTE 1)

**Note 1:** Values are over recommended operating conditions. Values are over all two power supply modes (V<sub>DD</sub> = 3.3V and V<sub>DD</sub> = 2.5V). XTAL frequency is 25 MHz.

#### TABLE 3-9: 5 MM × 5 MM VQFN PACKAGE THERMAL PROPERTIES

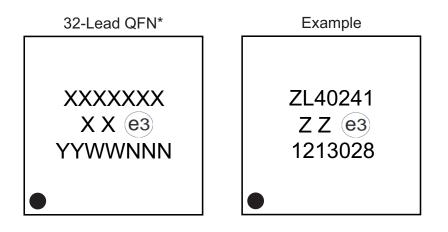
Parameter	Symbol	Conditions	Value	Units
Maximum ambient temperature	T <sub>A</sub>	_	85	°C
Maximum junction temperature	T <sub>J(MAX)</sub>	—	125	°C
		Still air	26.8	°C/W
Junction to ambient thermal resistance, Note 1	θ <sub>JA</sub>	1 m/s airflow	21.8	°C/W
		2.5 m/s airflow	19.9	°C/W
Junction to board thermal resistance	θ <sub>JB</sub>	—	10.8	°C/W
Junction to case thermal resistance	θ <sub>JC</sub>		19.5	°C/W
Junction to pad thermal resistance, Note 2	θ <sub>JP</sub>	Still air	6.5	°C/W
Junction to top-center thermal characterization parameter	Ψ <sub>JT</sub>	Still air	0.6	°C/W

**Note 1:**  $\theta_{JA}$  is the thermal resistance from junction to ambient when the package is mounted on a 4-layer JEDEC standard test board and dissipating maximum power.

**2:**  $\theta_{JP}$  is the thermal resistance from junction to the center exposed pad on the bottom of the package.

# 4.0 PACKAGE OUTLINE

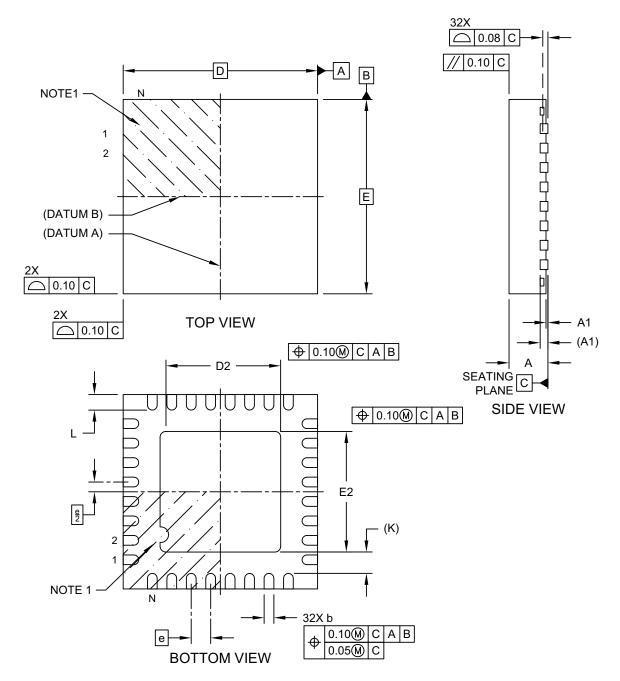
# 4.1 Package Marking Information



Legend	Y YY WW NNN @3 *	Product code or customer-specific information Year code (last digit of calendar year) Year code (last 2 digits of calendar year) Week code (week of January 1 is week '01') Alphanumeric traceability code Pb-free JEDEC <sup>®</sup> designator for Matte Tin (Sn) This package is Pb-free. The Pb-free JEDEC designator (e3) can be found on the outer packaging for this package.					
Note:	Note: In the event the full Microchip part number cannot be marked on one line, it will be carried over to the next line, thus limiting the number of available characters for customer-specific information. Package may or may not include the corporate logo.						
	Underbar	(_) and/or Overbar (⁻) symbol may not be to scale.					

#### 32-Lead 5 mm x 5 mm VQFN Package Outline and Recommended Land Pattern

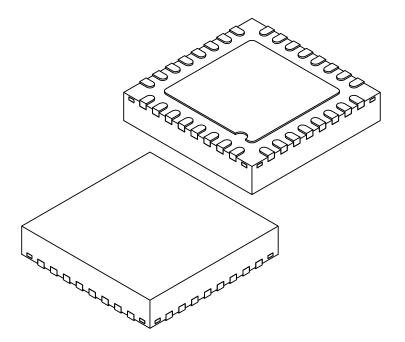
**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



Microchip Technology Drawing C04-25400 Rev A Sheet 1 of 2

#### 32-Lead 5 mm x 5 mm VQFN Package Outline and Recommended Land Pattern

For the most current package drawings, please see the Microchip Packaging Specification located at http:/ Note: /www.microchip.com/packaging



	Units			
Dimension	Limits	MIN	NOM	MAX
Number of Terminals	Ν		32	
Pitch	е		0.50 BSC	
Overall Height	Α	0.80	0.90	1.00
Standoff	A1	0.00	0.02	0.05
Terminal Thickness	A3		0.20 REF	
Overall Length	D		5.00 BSC	
Exposed Pad Length	D2	3.00	3.10	3.20
Overall Width	E		5.00 BSC	
Exposed Pad Width	E2	3.00	3.10	3.20
Terminal Width	b	0.20	0.25	0.30
Terminal Length	L	0.35	0.40	0.45
Terminal-to-Exposed-Pad	Κ	0.20	-	-

Notes:

1. Pin 1 visual index feature may vary, but must be located within the hatched area.

2. Package is saw singulated

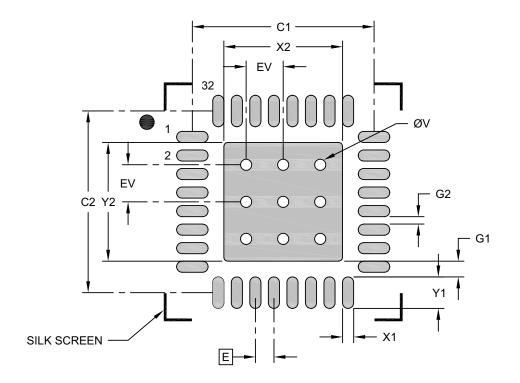
Dimensioning and tolerancing per ASME Y14.5M
 BSC: Basic Dimension. Theoretically exact value shown without tolerances.

REF: Reference Dimension, usually without tolerance, for information purposes only.

Microchip Technology Drawing C04-25400 Rev A Sheet 2 of 2

#### 32-Lead 5 mm x 5 mm VQFN Package Outline and Recommended Land Pattern

**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



#### RECOMMENDED LAND PATTERN

	Ν	<b>IILLIMETER</b>	S	
Dimension	Limits	MIN	NOM	MAX
Contact Pitch	E		0.50 BSC	
Optional Center Pad Width	X2			3.20
Optional Center Pad Length	Y2			3.20
Contact Pad Spacing	C1		4.90	
Contact Pad Spacing	C2		4.90	
Contact Pad Width (X32)	X1			0.30
Contact Pad Length (X32)	Y1			0.85
Contact Pad to Center Pad (X32)	G1	0.23		
Contact Pad to Contact Pad (X28)	G2	0.20		
Thermal Via Diameter	V		0.30	
Thermal Via Pitch	EV		1.00	

Notes:

1. Dimensioning and tolerancing per ASME Y14.5M

BSC: Basic Dimension. Theoretically exact value shown without tolerances.

2. For best soldering results, thermal vias, if used, should be filled or tented to avoid solder loss during reflow process

Microchip Technology Drawing C04-27400 Rev A

NOTES:

# APPENDIX A: DATA SHEET REVISION HISTORY

#### TABLE A-1: REVISION HISTORY

Revision	Section/Figure/Entry	Correction
DS20006783A (11-2023)	Various	Converted Microsemi data sheet ZL40241 to Micro- chip DS20006783A. Updated Figure 2-9 as requested by Applications. Minor text changes throughout.
DS20006783B (02-2025)	Table 3-4	Updated input duty cycle row and added note 5 to Table 3-4.

# **PRODUCT IDENTIFICATION SYSTEM**

To order or obtain information, e.g., on pricing or delivery, refer to the factory or the listed sales office.

					Example	s:	
Device	<u>X</u>	X	X	X	a) ZL4024	41LDG1:	
Part Number	Chip Carrier Type	Package	Media Type	Finish		Ten LVCMOS Output Low Additive Jitter Fanout Buffer, Leadless Chip Carrier, 32-Lead 5 mm x 5 mm VQFN,	
Device:		ZL40241: Ten LVCMOS Output Low Additive Jitter Fanout Buffer				490/Tray, Pb Free with Matte Sn Lead Finish, RoHS e3 Compliant	
	Duilei					b) ZL40241LDF1:	
Chip Carrier Type	: L = Leadles	L = Leadless Chip Carrier				Ten LVCMOS Output Low Additive Jitter Fanout Buffer, Leadless Chip Carrier, 32-Lead 5 mm x 5 mm VQFN,	
Package:	D = 32-Lead	D = 32-Lead 5 mm x 5 mm VQFN				4,000/Reel, Pb Free with Matte Sn Lead Finish, RoHS e3 Compliant	
Media Type:	G = 490/Tra F = 4,000/R						
Finish:	1 = Pb Free	1 = Pb Free with Matte Sn Lead Finish, RoHS e3 Compliant					
					Note 1:	Tape and Reel identifier only appears in the catalog part number description. This identifie	
						is used for ordering purposes and is not printed on the device package. Check with your Microchip Sales Office for package availability with the Tape and Reel option.	

# ZL40241

NOTES:

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